



Key: IEEE JNL = IEEE Journal or Magazine, IEE JNL = IEE Journal or Magazine, IEEE CNF = IEEE Conference, IEE CNF = IEE Conference, IEEE STD = IEEE Standard

1. **A New Algorithm for Reachability Testing of Concurrent Programs**
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2. **Pseudorandomness for approximate counting and sampling**
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5. **A comparison of stuck-at fault coverage and I_{DDQ} testing on defect levels**
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9. **A hybrid distributed test generation method using deterministic and genetic algorithms**
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16. **Continuous signature monitoring: low-cost concurrent detection of processor control errors**
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19. **Optimal configuring of multiple scan chains**
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- 21. Recursive learning: a new implication technique for efficient solutions to CAD problems-test, verification, and optimization**

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- 22. Distributed control schemes for fast arbitration in large crossbar networks**

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L1	32	(generate generated generation generating) and (compare comparator compared comparison comparing) and ((test TESTING TESTER TESTED) with ((integrated adj circuit) circuit semiconductor ic memory logic)) and (expect\$ with result) and (fail failure failed failing error erroneous) and "714"/\$.ccls. and (range window).ab.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/11 09:37
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S3	39	("5530370" "5390183" "6317700" "6219809" "6219809" "6510398" "6138259" "6369601" "6815943" "6850085" "5544175" "5732047" "5919270" "4779273" "4870346" "4807147" "5619588" "5907628" "5325360" "6760582" "6292830" "6349270" "5231598" "5398252" "6505274" "6401225" "6493841" "6195627" "6212491" "6188253" "5968194" "6360180" "5777932" "5260947" "5610925" "5701309" "6243841" "4583041" "4797886" "4827437" "4855969" "4860291" "4862071" "4888715" "4998025" "5381421" "5412662" "5422892" "5500862" "5590136").pn. and (generat\$) and compar\$ and test\$	USPAT	OR	ON	2006/01/09 10:07
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S5	62940	(generate generated generation generating) and (compare comparator compared comparison comparing) and ((test TESTING TESTER TESTED) with ((integrated adj circuit) circuit semiconductor ic memory logic)) and result	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/10 08:41
S6	4691	(generate generated generation generating) and (compare comparator compared comparison comparing) and ((test TESTING TESTER TESTED) with ((integrated adj circuit) circuit semiconductor ic memory logic)) and (expect\$ with result)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/10 08:42
S7	3833	(generate generated generation generating) and (compare comparator compared comparison comparing) and ((test TESTING TESTER TESTED) with ((integrated adj circuit) circuit semiconductor ic memory logic)) and (expect\$ with result) and (fail failure failed failing error erroneous)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/10 08:43
S8	1149	(generate generated generation generating) and (compare comparator compared comparison comparing) and ((test TESTING TESTER TESTED) with ((integrated adj circuit) circuit semiconductor ic memory logic)) and (expect\$ with result) and (fail failure failed failing error erroneous) and "714"/\$.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/10 08:43
S9	545	(generate generated generation generating) and (compare comparator compared comparison comparing) and ((test TESTING TESTER TESTED) with ((integrated adj circuit) circuit semiconductor ic memory logic)) and (expect\$ with result) and (fail failure failed failing error erroneous) and "714"/\$.ccls. and (range window)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/01/11 09:36